

Figure 1 consists of four cross-sectional views of a semiconductor device, labeled (A), (B), (C), and (D). Each view shows a substrate 2 with a layer 1 or 1A on top. A layer 3 is also present. In (A), layer 3 is on top of layer 1. In (B), (C), and (D), layer 3 is on top of layer 1A. The layers are labeled with numbers 1, 2, 3, 1A, and 12. A dashed line labeled 11 is also shown in each view. An arrow labeled S points to the top surface of the device in each view.

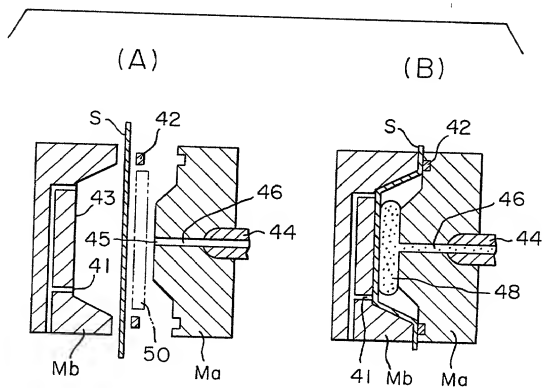


FIG. 3